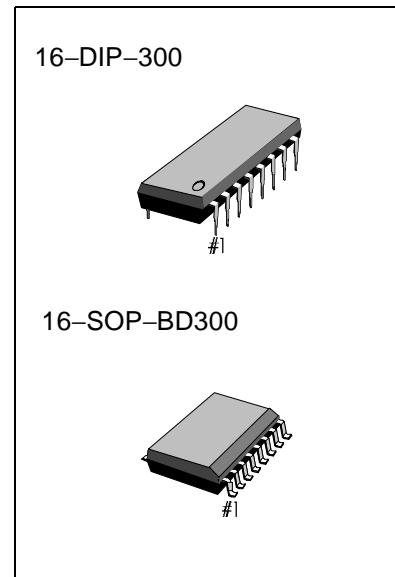


INTRODUCTION

The S5T8554B03 consists of on-chip PCM encoders, decoders (PCM CODECs) and PCM line filter. This device provides all the functions required to interface a full-duplex voice telephone circuit, digital answering phone. This device is designed to perform the transmit encoding and receive decoding as well as the transmit and receive filtering function in PCM system. Also it is intended to be used at the analog termination of a PCM line / trunk. This device provide the Band pass filtering of the analog signals prior to encoding and after decoding. This combination device performs the encoding and decoding of voice and call progress tones as well as the signaling and supervision information.



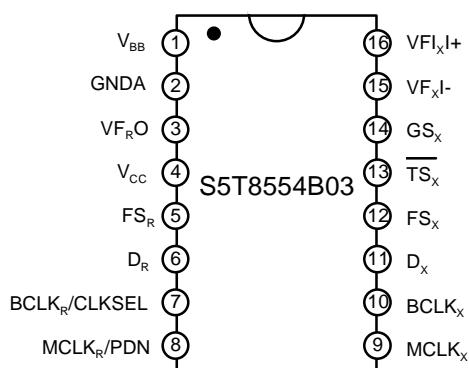
FEATURES

- Complete CODEC and filtering system
- Encoding / Decoding : 8 bits μ -law PCM
- On-chip auto zero, sample and hold, and precision voltage references
- Low power dissipation : 60mW (operating)
3mW (standby)
- $\pm 5V$ operation
- TTL or CMOS compatible
- Automatic power down

ORDERING INFORMATION

Device	Package	Operating Temperature
S5T8554B03-D0B0	16-DIP-300	0 ~ + 70°C
S5T8554B03-S0B0	16-SOP-BD300	

PIN CONFIGURATION



BLOCK DIAGRAM

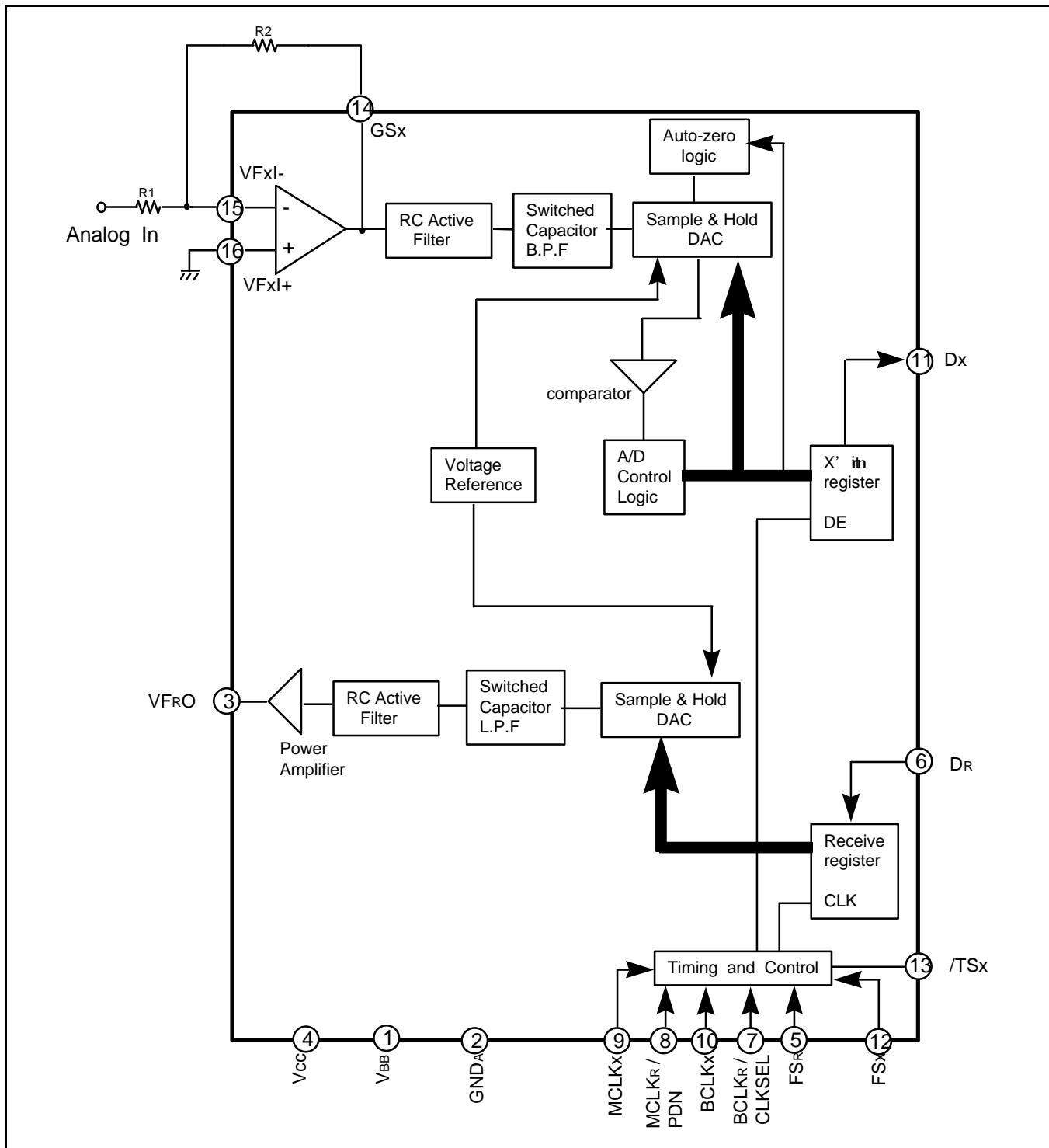


Figure 1.

PIN DESCRIPTION

Pin No	Symbol	Description
1	V _{BB}	V _{BB} = -5V ± 5%
2	GNDA	Analog ground
3	V _{FRO}	Analog output of the receiver filter
4	V _{CC}	V _{CC} = + 5V ± 5%
5	FS _R	Receive frame sync pulse. 8kHz pulse train.
6	D _R	PCM data input
7	BCLK _R / CLKSEL	Logic input which selects either 1.536MHz/1.544MHz or 2.048MHz for master clock in normal operation and BCLKx is used for both TX and RX directions. Alternately direct clock input available, vary from 64kHz to 2.048MHz.
8	MCLK _R / PDN	When MCLK _R is connected continuously high, the device goes powered down . Normally connected continuously low, MCLKx is selected for all DAC timing. Alternately direct 1.536MHz/1.544MHz or 2.048MHz clock input is available.
9	MCLK _{Xn}	1.536MHz/1.544MHz or 2.048MHz clock input is available
10	BCLK _X	May be vary from 64kHz 2.048MHz, but BCLKx is externally tied with MCLKx in normal operation.
11	D _X	PCM data output.
12	FS _X	TX frame sync pulse. 8kHz pulse train.
13	TS _X	Changed from high to low during the encoder timeslot. Open drain output.
14	GS _X	Analog output of the TX input amplifier. Used to set gain through external resistor between pin 14 to pin 15.
15	V _{FXI-}	Inverting input stage of the TX analog signal.
16	V _{FXI+}	Non-inverting input stage of the TX analog signal.e

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Characteristic	Symbol	Value	Unit
Positive Supply Voltage	V _{CC}	+7	V
Negative Supply Voltage	V _{BB}	-7	V
Voltage at any Analog Input or Output	V _{I(A)}	V _{CC} + 0.3 to V _{BB} - 0.3	V
Voltage at any Digital Input or Output	V _{I(D)}	V _{CC} + 0.3 to GNDA - 0.3	V
Operating Temperature Range	T _A	0 to 70	°C
Storage Temperature Range	T _{STG}	-65 to +150	°C
Lead Temperature Range (soldering, 10 sec)	T _{LEAD}	300	°C

ELECTRICAL CHARACTERISTICS(Unless otherwise specified : $T_a = 0^\circ\text{C}$ to 70°C , $V_{CC} = 5V \pm 5\%$, $V_{BB} = -5V \pm 5\%$, $GND_A = 0V$)

Characteristic	System	Test Conditions	Min.	Typ.	Max.	Unit
Power Dissipation						
Power down Current	$I_{CC(\text{down})}$	No Load	–	0.5	3.0	mA
Power down Current	$I_{BB(\text{down})}$	No Load	–	0.05	1.0	mA
Active Current	$I_{CC(A)}$	No Load	–	6.0	10	mA
Active Current	$I_{BB(A)}$	No Load	–	6.0	10	mA
Digital Interface						
Input Low Voltage	V_{IL}	–	–	–	0.6	V
Input High Voltage	V_{IH}	–	2.2	–	–	V
Input Low Current	I_{IL}	$GND_A < V_{IN} < V_{IL}$, all digital input	–15	–	15	μA
Input High Current	I_{IH}	$V_{IH} < V_{IN} < V_{CC}$	–15	–	15	μA
Output Low Voltage	V_{OL}	$D_x, I_L = 3.2 \text{ mA}$ $SIG_R, I_L = 1.0 \text{ mA}$ $/TSx, I_L = 3.2 \text{ mA}$, open drain	–	–	0.4	V
Output High Voltage	V_{OH}	$D_x, I_H = -3.2 \text{ mA}$ $SIG_R, I_H = -1.0 \text{ mA}$	2.4 2.4	–	–	V
Output Current in High impedance state (Tri-state)	$I_{OH(HZ)}$	$D_x, GND_A < V_o < V_{CC8}$	–15	–	15	μA
Analog Interface with Receiver Filter						
Output Resistance	R_o	pin VF _{RO}	–	1	3	Ω
Load Resistance	R_L	$VF_{RO} = \pm 2.5V$	600	–	–	Ω
Load Capacitance	C_L	–	–	–	500	pF
Output Capacitance	C_L	–	–200	–	200	mV
Analog Interface with Transmit input Amp						
Input Leakage Current	I_{LKG}	$-2.5V < V < +2.5V, VF_{xI+} \text{ or } VF_{xI-}$	–200	–	200	nA
Input Resistance	R_I	$-2.5V < V < +2.5V, VF_{xI+} \text{ or } VF_{xI-}$	10	–	–	$M\Omega$
Output Resistance	R_o	closed loop, unity gain	–	1	3	Ω
Load Resistance	R_L	GSx	10	–	–	k Ω
Load Capacitance	C_L	GSx	–	–	50	pF
Output Dynamic Range	$V_{OD(TX)}$	$GSx, R_L < 10k\Omega$	± 2.8	–	–	V
Voltage Gain	G_v	$VF_{xI+} \text{ to } GSx$	5000	–	–	V/V
Unity Gain bandwidth	B_W	–	1	2	–	MHz
Offset Voltage	$V_{IO(TX)}$	–	–20	–	20	mV
Common-mode Voltage	$V_{CM(TX)}$	$CMRRxA > 60\text{dB}$	–2.5	–	2.5	V
Common mode rejection ratio	CMRR	DC test	55	–	–	dB
Power supply rejection ratio	PSRR	DC test	55	–	–	dB



ELECTRONICS

TIMING CHARACTERISTICS(Unless otherwise specified : $T_a = 0^{\circ}\text{C}$ to 70°C , $V_{CC} = 5\text{V} \pm 5\%$, $V_{BB} = -5\text{V} \pm 5\%$, $GND_A = 0\text{V}$)

Characteristic	System	Test Conditions	Min.	Typ.	Max.	Unit
Frequency of Master Clock	fMCK	Depends on the device used and the BCLKR/CLKSEL pin. MCLKx and MCLK	–	1.536	–	MHz
			–	1.544	–	
			–	2.048	–	
Rise time of Bit Clock	tR(BCK)	tPB = 488ns	–	–	50	nS
Fall Time of Bit Clock	tF(BCK)	tPB = 488ns	–	–	50	nS
Hold Time for Bit Clock low to Frame sync	tH(LFS)	Long Frame only	0	–	–	nS
Hold Time for Bit Clock High to Frame sync	tH(HFS)	Short Frame only	0	–	–	nS
Set-up Time from Frame sync to Bit Clock low	tsu(FBCL)	Long Frame only	80	–	–	nS
Delay time from BCLKx High to data valid	td(HDV)	Load = 150pF + 2 LSTTL loads	0	–	180	nS
Delay time to /TSx low	td(/TSXL)	Load = 150pF + 2 LSTTL loads	–	–	140	nS
Delay time from BCLKx low to data output disable	td(LDD)		50	–	165	nS
Delay Time to valid data from FSx or BCLKx	td(VD)	CL = 0 pF to 150 pF Whichever comes later.	20	–	165	nS
Set-up Time from DR valid to BCLK x/R low	tsu(DRBL)	–	50	–	–	nS
Hold time from BCLK x/R low to DR invalid	tH(BLDR)	–	50	–	–	nS
Set-up time from FS x/R to BCLK x/R low	tsu(FBLS)	Short Frame sync pulse (1 or 2 bit clock periods long) : note1	50	–	–	nS
Width of master clock High	tw(MCKH)	MCLKx and MCLKR	160	–	–	nS
Width of master clock Low	tw(MCKL)	MCLKx and MCLKR	160	–	–	nS
Rise Time of Master clock	tR(MCK)	MCLKx and MCLKR	–	–	50	nS
Fall Time of Master clock	tF(MCK)	MCLKx and MCLKR	–	–	50	nS
Set-up time from BCLKx High (FSx in Long Frame Sync mode) to MCLKx falling edge	tsu(BHMF)	1'st bit clock after the leading edge of FSx	50	–	–	nS
Period of Bit Clock	tCK	–	485	488	15.725	nS
Width of Bit clock High	tw(BCKH)	$V_{IH} = 2.2\text{V}$	160	–	–	nS
Width of Bit clock Low	tw(BCKL)	$V_{IL} = 0.6\text{V}$	160	–	–	nS
Hold time from BCLK x/R to FS x/R low	tH(BLFL)	Short Frame sync pulse (1 or 2 bit clock periods long) : note1	100	–	–	nS

TIMING DIAGRAM

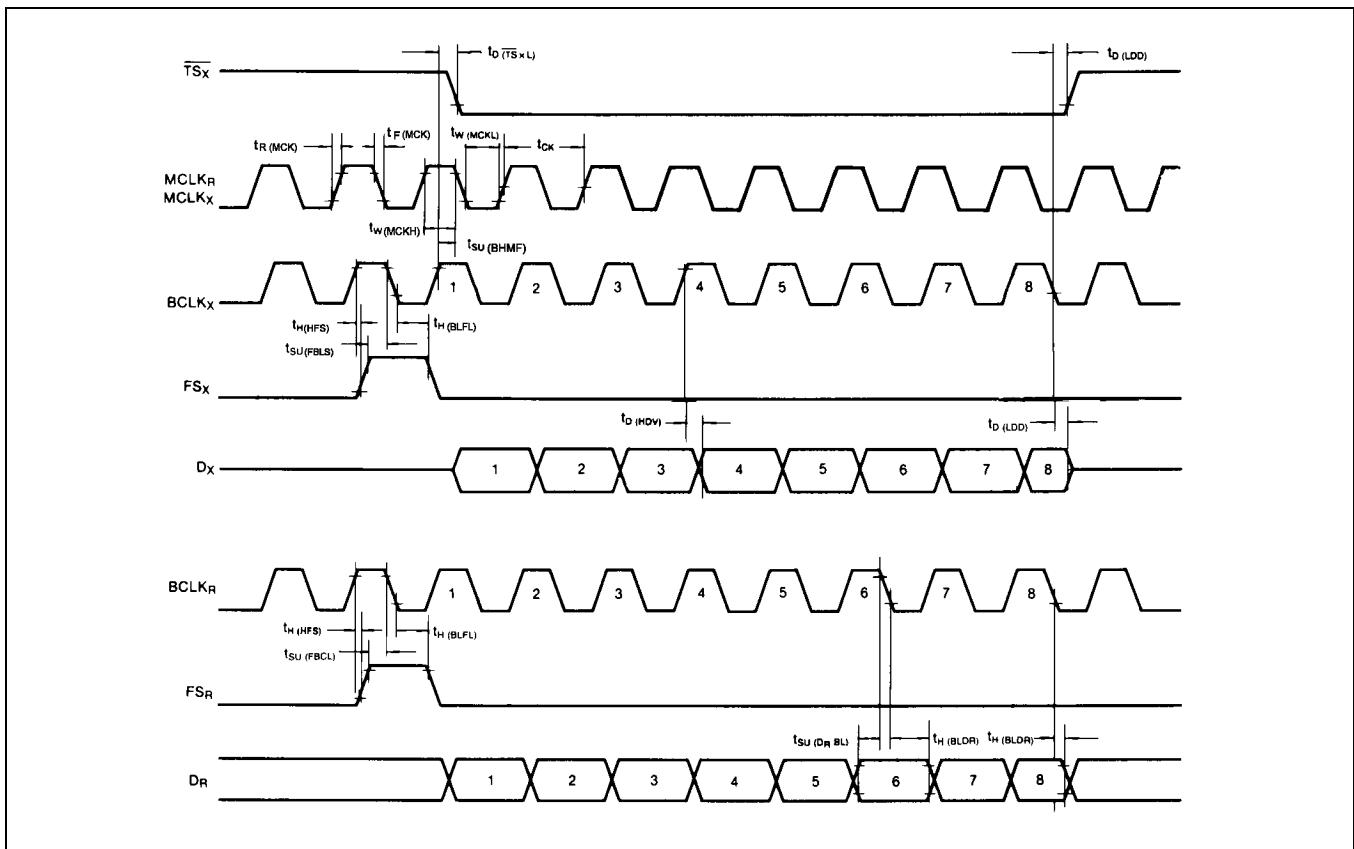


Figure 2. Short Frame SYNC Timing

TIMING DIAGRAM (Continued)

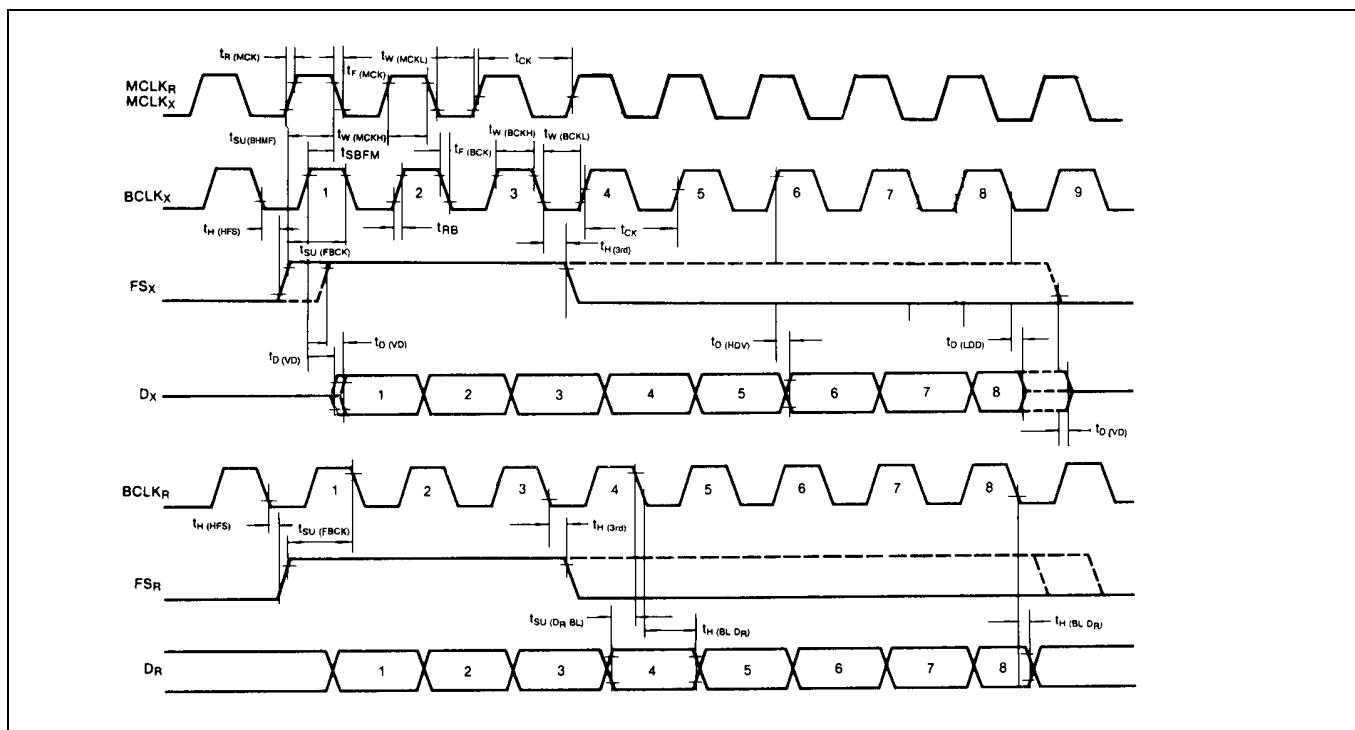


Figure 3.

NOTE: 1. For Short Frame Sync timing ,FSx and FSR must go high while their respective bit clocks has high level

TRANSMISSION CHARACTERISTICS

(Unless otherwise specified: Ta = 0°C to 70°C, V_{CC} = 5V ± 5%, V_{BB} = -5V ± 5%, GND_A = 0V, f = 1.02kHz
Vin = 0dBm0, transmit input amplifier connected for unity-gain, non-inverting)

Characteristic	System	Test Conditions	Min.	Typ.	Max.	Unit
Amplitude Response						
Receive Gain, Absolute	G _V (ARX)	Ta = 25°C, V _{CC} = 5V, V _{BB} = -5V Input = Digital code sequence for 0dBm0 signal at 1020Hz	-1.5	-	1.5	dB
Receive Gain, Relative to G _V (RRX)	G _V (RRX)	f = 0Hz to 3000Hz f = 3300Hz f = 3400Hz	-0.6 -0.55 -1.5	-	0.5 0.5 1.5	dB
Absolute Receive Gain Variations with temperature	ΔG _V (ARX) /ΔT	Ta = 0°C to 70°C	-	-	± 0.1	dB

TRANSMISSION CHARACTERISTICS (Continued)

(Unless otherwise specified: $T_a = 0^\circ\text{C}$ to 70°C , $V_{cc} = 5\text{V} \pm 5\%$, $V_{BB} = -5\text{V} \pm 5\%$, $GND_A = 0\text{V}$, $f = 1.02\text{kHz}$
 $V_{in} = 0\text{dBm0}$, transmit input amplifier connected for unity-gain, non-inverting)

Characteristic	System	Test Conditions	Min.	Typ.	Max.	Unit
Receive Gain Variations with level	$\Delta G_{V(RXL)}$	Sinusoidal test method; reference input PCM code correspond to an ideally encoded -10dBm0 signal PCM level = -40dBm0 to $+3\text{dBm0}$ PCM level = -50dBm0 to -40dBm0	-0.4 -0.8	-	0.4 0.8	dB
Receive output drive level		$R_L = 600\Omega$	-2.5	-	2.5	V
Absolute level	$V_{O(RX)}$ V_{AL}	Normal 0dBm0 level is same as 4- dBm (600Ω)	-	1.2276	-	Vrms
Max overload level	$V_{OL(MAX)}$	Max overload level (3.17dBm0)	-	2.501	-	V_{PK}
Transmit gain, absolute	$G_{V(ATX)}$	$T_a = 25^\circ\text{C}$, $V_{cc} = 5\text{V}$, $V_{BB} = -5\text{V}$ Input at $GS_x = 0\text{dBm0}$ at 1020Hz	-1.5	-	1.5	dB
Transmit gain, relative to $G_{V(ATX)}$	$G_{V(RTX)}$	$f = 16\text{Hz}$ $f = 50\text{Hz}$ $f = 60\text{Hz}$ $f = 200\text{Hz}$ $f = 300\text{Hz} - 3000\text{Hz}$ $f = 3300\text{Hz}$ $f = 3400\text{Hz}$ $f = 4000\text{Hz}$ $f = 4600\text{Hz}$ and above, measure response from 0Hz to 4kHz	-2 -0.5 -0.55 -1.5	-	-35 -25 -21 -0.5 0.5 0.5 -0.5 -10 -25	dB
Absolute transmit gain variations with temperature	$\Delta G_{V(ATX)}$ $/\Delta T$	$T_a = 0^\circ\text{C}$ to 70°C	-	-	± 0.1	dB
Transmit gain variations with level	$\Delta G_{V(TXL)}$	Sinusoidal test method ; Reference level = -10dBm0 $V_{F_XI+} = -40\text{dBm0}$ to $+3\text{dBm0}$ $V_{F_XI+} = -50\text{dBm0}$ to -40dBm0	-0.4 -0.8	-	0.4 0.8	dB
Envelope Delay Distortion with Frequency						
Receive Delay, Absolute	$t_{D(ARX)}$	$f = 1600\text{Hz}$	-	-	200	μs
Receive Delay, Relative to t_D (ARX)	$t_{D(RRX)}$	$f = 500\text{Hz} - 1000\text{Hz}$ $f = 1000\text{Hz} - 1600\text{Hz}$ $f = 1600\text{Hz} - 2600\text{Hz}$ $f = 2600\text{Hz} - 2800\text{Hz}$ $f = 2800\text{Hz} - 3000\text{Hz}$	-40 -30	-	90 125 175	μs
Transmit Delay, Absolute	$t_{D(ATX)}$	$f = 1600\text{Hz}$	-	-	315	μs

TRANSMISSION CHARACTERISTICS (Continued)

(Unless otherwise specified: $T_a = 0^\circ\text{C}$ to 70°C , $V_{cc} = 5\text{V} \pm 5\%$, $V_{BB} = -5\text{V} \pm 5\%$, $GND_A = 0\text{V}$, $f = 1.02\text{kHz}$
 $V_{in} = 0\text{dBm0}$, transmit input amplifier connected for unity-gain, non-inverting)

Characteristic	System	Test Conditions	Min.	Typ.	Max.	Unit
Transmit Delay, Relative to $t_{D(ATX)}$	$t_{D(RTX)}$	$f = 500\text{Hz} - 600\text{Hz}$ $f = 600\text{Hz} - 800\text{Hz}$ $f = 800\text{Hz} - 1000\text{Hz}$ $f = 1000\text{Hz} - 1600\text{Hz}$ $f = 1600\text{Hz} - 2600\text{Hz}$ $f = 2600\text{Hz} - 2800\text{Hz}$ $f = 2800\text{Hz} - 3000\text{Hz}$	—	—	220 145 75 40 75 105 155	μs
Noise						
Receive Noise, C Message Weighted	N_{RXC}	PCM code equals alternating positive and negative zero, S5T8554B03	—	—	18	dBrn C0
Transmit Noise, C Message Weighted	N_{TXC}	S5T8554B03	—	—	15	dBrn C0
Noise, Single Frequency	NSF	$f = 0\text{kHz}$ to 100kHz , loop around measurement, $VFXI+ = 0\text{Vrms}$	—	—	-53	dBrn C0
Positive Power Supply Rejection, Transmit	$PSRR_{(PTX)}$	$VFXI+ = 0\text{ Vrms}$, $V_{cc} = 5.0\text{ VDC} + 100\text{mVrms}$ $f = 0\text{kHz} - 50\text{kHz}$	25	—	—	dB
Negative Power Supply Rejection, Transmit	$PSRR_{(NTX)}$	$VFXI+ = 0\text{ Vrms}$, $V_{BB} = -5.0\text{ VDC} + 100\text{mVrms}$ $f = 0\text{kHz} - 50\text{kHz}$	25	—	—	dB
Positive Power Supply Rejection, Receive	$PSRR_{(PRX)}$	PCM code equals positive zero $V_{cc} = 5.0\text{VDC} + 100\text{mVrms}$ $f = 0\text{Hz} - 4000\text{Hz}$ $f = 4\text{kHz} - 25\text{kHz}$	25 25	—	—	dB dB
Negative Power Supply Rejection, Receive	$PSRR_{(NRX)}$	PCM code equals positive zero $V_{BB} = -5.0\text{VDC} + 100\text{mVrms}$ $f = 0\text{Hz} - 4000\text{Hz}$ $f = 4\text{kHz} - 25\text{kHz}$	25 25	—	—	dB dB
Spurious Out-Band Signals at the Channel Output	SOS	Loop around measurement, 0dBm0 , $300\text{Hz} - 3400\text{Hz}$ input PCM applied to DR, Measure individual image signals at VFRO $4600\text{Hz} - 7600\text{Hz}$ $7600\text{Hz} - 100,000\text{Hz}$	—	—	-28 -35	dB
Distortion						
Signal to Total Distortion Transmit or Receive Half-Channel	THD_{TX} THD_{RXa}	Sinusoidal test method; level = 3.0dBm0 = 0dBm0 to 30dBm0 = -40dBm0 XMT RCV	28 30 25 25	—	—	dB

TRANSMISSION CHARACTERISTICS (Continued)

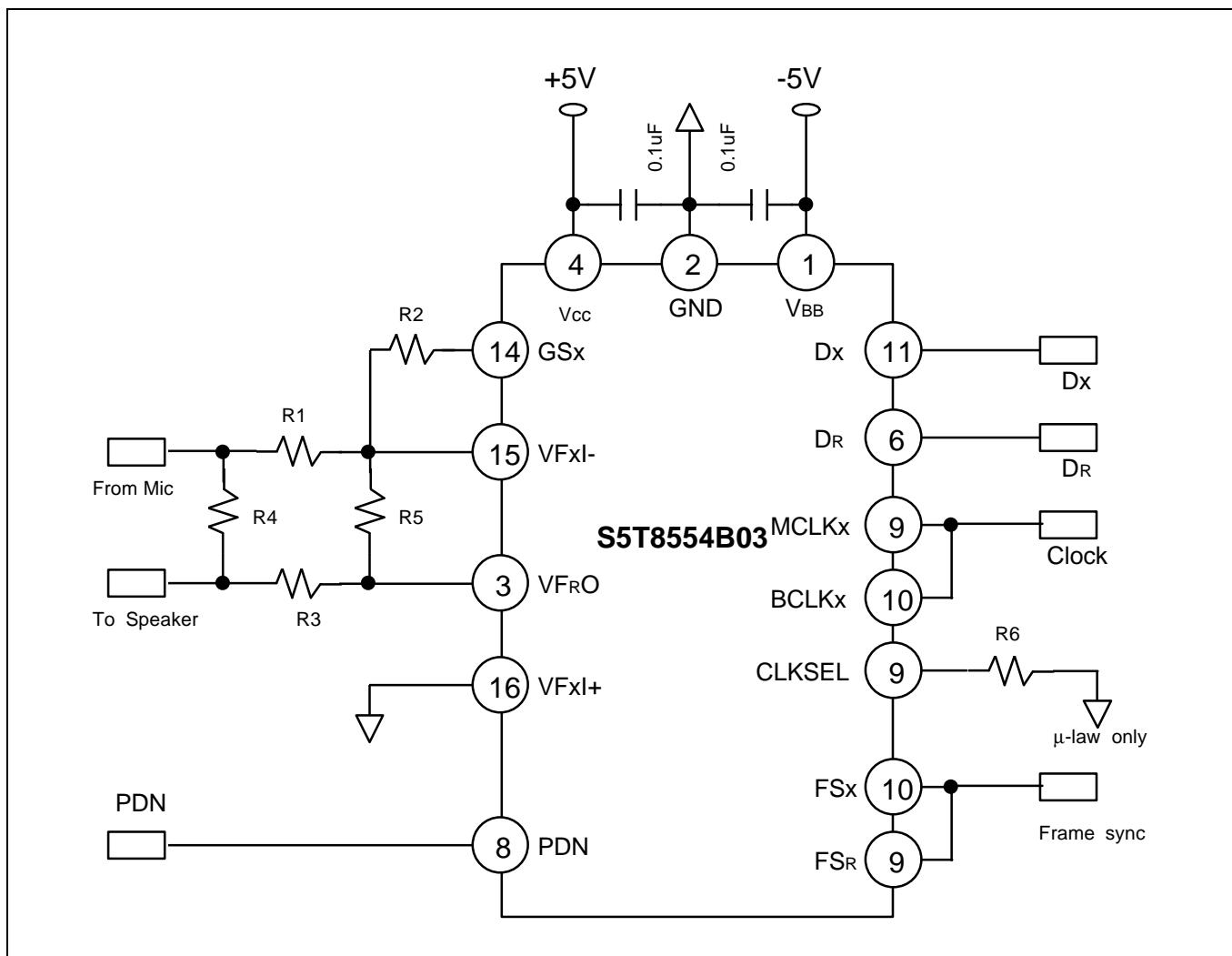
(Unless otherwise specified: $T_a = 0^\circ\text{C}$ to 70°C , $V_{cc} = 5\text{V} \pm 5\%$, $V_{BB} = -5\text{V} \pm 5\%$, $GND_A = 0\text{V}$, $f = 1.02\text{kHz}$
 $V_{in} = 0\text{dBm0}$, transmit input amplifier connected for unity-gain, non-inverting)

Characteristic	System	Test Conditions	Min.	Typ.	Max.	Unit
Single Frequency Distortion, Transmit	$\text{THD}_{SF(TX)}$	—	—	—	-41	-dB
Single Frequency Distortion, Receive	$\text{THD}_{SF(RX)}$	—	—	—	-41	-dB
Intermodulation Distortion	THD_{IMD}	Loop around measurement, $V_{FXI+} = -4\text{dBm0}$ to -21dBm0 , two frequencies in the range 300Hz – 3400Hz	—	—	-35	-dB
Crosstalk						
Transmit to Receive Crosstalk, 0dBm0 Transmit level	$CT_{(TX-RX)}$	$f = 300\text{Hz} - 3400\text{Hz}$ $D_R = \text{Steady PCM code}$	—	-90	-75	dB
Receive to Transmit Crosstalk, 0dBm0 Receive level	$CT_{(RX-TX)}$	$f = 300\text{Hz} - 3400\text{Hz}$, $V_{FXI} = 0\text{V}$	—	-90	-70 (note 1)	dB

NOTE: $CT_{(RX-TX)}$ is measured with a -40dBm0 activating signal applied at V_{FXI+}

		m-Law PCM : S5T8554B03
VIN (at GSX) = + Full Scale		1 0 0 0 0 0 0 0
VIN (at GSx) = 0V		1 1 1 1 1 1 1 1 0 1 1 1 1 1 1 1
VIN (at GSx) = - Full Scale		0 0 0 0 0 0 0 0

APPLICATION CIRCUIT



NOTES:

1. Supposing desired Line Termination Impedance $R_L = 600\Omega$
It is 0 dBm - 0.77459 Vrms
2. Tx Gain = $20 \log (R_2 / R_1)$, $R_1 + R_2 < 100k\Omega$
or The Correspondence of 0 dBm0 = 4 dBm

Selection of Master Clock Frequency

BCLKR / CLKSEL	Master Clock Frequency
Clocked 0 1(or Open)	1.536 / 1.544MHz 2.048MHz 1.536 / 1.544MHz

NOTES